Notice of References Cited

Application/Control No. 10/808,464	Reexamination	Applicant(s)/Patent Under Reexamination TAGUCHI ET AL.	
Examiner	Art Unit		
Helene Klemanski	1755	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0187733 A1	09-2004	Ogawa et al.	106/031.13
*	В	US-2004/0194660 A1	10-2004	Taguchi et al.	106/031.43
*	С	US-2004/0200385 A1	10-2004	Taguchi et al.	106/031.43
*	D	US-2004/0246321 A1	12-2004	Takashima et al.	347/100
*	Е	US-2005/0001890 A1	01-2005	Taguchi et al.	347/100
*	F	US-6,939,399 B2	09-2005	Yabuki, Yoshiharu	106/31.27
*	G	US-2004/0024085 A1	02-2004	Ishizuka et al.	523/160
*	H	US-2004/0099181	05-2004	Tateishi et al.	106/031.47
*	1	US-2004/0089200	05-2004	Fujiwara et al.	106/031.48
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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